

AD-A101 337

FOREIGN TECHNOLOGY DIV WRIGHT-PATTERSON AFB OH  
INVESTIGATION INTO THE LASER DAMAGE OF THE PHOTO-SENSITIVE ELEM--ETC(U)  
JUN 81 L XUHNAO, Q JUNWEN, J YINHUA

F/6 20/5

UNCLASSIFIED

FTD-ID(RS)T-0173-81

NL

For  
AFSST

B

337

END  
DATE  
FILED  
7-21-81  
OTIC

2  
ADA101337

FTD-ID(RS)T-0173-81

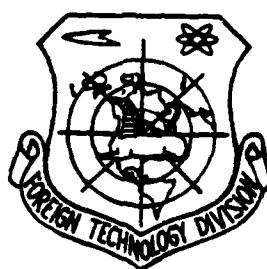
## FOREIGN TECHNOLOGY DIVISION



INVESTIGATION INTO THE LASER DAMAGE OF THE PHOTO-SENSITIVE  
ELEMENTS IN VULCANIZED LEAD (LEAD SULFIDE)

by

Liu Xuhnao, Qui Junwen, et al.



DTIC  
ELECTED  
JUL 14 1981  
S D  
H

Approved for public release;  
distribution unlimited.



81 7 14 082

FTD-ID(RS)T-0173-81

## EDITED TRANSLATION

14) FTD-ID(RS)T-0173-81

15 Jun 1981

MICROFICHE NR: FTD-C-81-00531

6) INVESTIGATION INTO THE LASER DAMAGE OF THE  
PHOTO-SENSITIVE ELEMENTS IN VULCANIZED LEAD  
(LEAD SULFIDE)

By: Liu/Xuhnao, Qui/Junwen Jan/Yinhua Bai/Chanwen Hui/Linkai

English pages: 16

Source: Shanghai Jijuang  
pp. 25-30

Country of origin: (China)

Translated by: SCITRAN

F33657-78-D-0619

Requester: FTD/TQTD

Approved for public release; distribution  
unlimited.

THIS TRANSLATION IS A RENDITION OF THE ORIGINAL FOREIGN TEXT WITHOUT ANY ANALYTICAL OR EDITORIAL COMMENT. STATEMENTS OR THEORIES ADVOCATED OR IMPLIED ARE THOSE OF THE SOURCE AND DO NOT NECESSARILY REFLECT THE POSITION OR OPINION OF THE FOREIGN TECHNOLOGY DIVISION.

PREPARED BY:

TRANSLATION DIVISION  
FOREIGN TECHNOLOGY DIVISION  
WP-AFB, OHIO.

FTD-ID(RS)T-0173-81

Date 15 Jun 1981

Investigation into the Laser Damage of the Photo-Sensitive  
Elements in Vulcanized Lead (Lead Sulfide)

Liu Xuhnao	Hui Linkai	Liu Yupu
Qui Junwen	Li Qun	Fan Junping
Jan Yinhua	Pu Baodan	Wan Tziyin
Bai Chanwen	Tan Baoshin	Zho Dingin

Translation of "hiuhwagen dunmin yuangen de diguan xunzhan  
yenjiu", source unknown, 25 - 30 pps.

Accession For	
NTIS GRA&I	<input checked="" type="checkbox"/>
DTIC TAB	<input type="checkbox"/>
Unannounced	<input type="checkbox"/>
Justification	
By	
Distribution/	
Availability Codes	
Avail and/or	
Dist	Special
A	

## ABSTRACT

This paper reports on the experimental results of laser damage of photosensitive detectors in vulcanized lead. We have studied the factors in the laser damage threshold and the threshold effect on the PbS photo-sensitive detectors. The lasers utilized all have a wavelength of 1.06 microns, but their pulse widths and power densities vary by several orders of magnitude.

### I. Introduction

There have been many studies performed on the interaction between lasers and various materials, especially metals [1]. In particular, a variety of analytical models have been proposed for damage handling [3 - 9]. However, there have been comparatively few studies performed for laser damage on semi-conductors and detectors. Only in the last few years have more systematic studies been made on these materials [10-15].

In order to understand the interaction between lasers and semiconductors, we have selected the photo-sensitive PbS detector for studying laser damage. First we observe PbS under an irradiation from 1.06 micron lasers with various pulse widths. The signal-to-noise ratio varies with the rules on light density. We observe its laser damage threshold, and compare it to that of metals, etc. The result of our experiments shows that the PbS damage threshold value is much lower than that of metals, and that our findings basically

coincide with those obtained by Kruer [16].

## II. Requirements of the Experiment

We used a 1.06 micron solid laser device in the experiment on PbS photo-sensitive detectors and studied the related laser damage elements. We tried to obtain a laser pulse width with varying threshold of 8 - 10 orders of magnitude (from tens of seconds to tens of nanoseconds). We selected separately several kinds of solid laser devices. We used the YAG:Nd<sup>3+</sup> laser device (with an attached time-synchronized turntable valve) to experiment on the damage, in time intervals from 1 to tens of seconds. We also used neodymium glass laser devices to obtain experimental data with 2 millisecond and 0.2 millisecond duration. We also used a photocurrent, Q-switched neodymium glass laser device to conduct damage experiments using a laser with a pulse width of 50 nanoseconds. The experimental arrangement is shown in Figure 1.

In order to obtain the variation threshold on 10-12 orders of magnitude ( $10^{-4}$  -  $10^8$  W/cm<sup>2</sup>), we passed the laser irradiation energy density and power density of the PbS in a semiconductor, photosensitive detector through an increment/decrement light filter (to pass through some pre-selected, varying focal length of the lens, and the distance between the PbS element and the lens). This was done to vary the laser pulse width and the output energy in order to achieve the above threshold.

In order to calculate accurately the irradiation energy density of the PbS detectors, we set a standard for the energy-measuring instrument before the experiment, and we

measured the dimensions of the light bands. In every experiment we measured the output energy with care, and we used a gas laser to fix the position of irradiation on the detector.

We used a PbS photosensitive detector of differing structures to conduct the damage experiments. We also at the same time used semiconductor or germanium segments, and ZnS with coated semiconductor germanium membrane to undergo laser damage experiments.

The kinds of PbS detectors used in the experiments have the following structures:

(1) PbS photosensitive surface (the optical segment) receives direct laser illumination. There are two kinds of optical segments of this type: one with combined ammonia treatment, and one that has undergone high temperature treatment. The structure is shown in Figure 2.

(2) The PbS photosensitive receiving detector has a quartz window (for passing through the light). The quartz window (sliding cover) is tightly bonded to the photosensitive surface of the PbS. This is shown in Figure 3.

(3) Its structure is basically the same as (2). However, the windows are quartz or germanium, and there is a fixed gap from the PbS photosensitive surface.

(4) The window is a PbS photosensitive detector in the doped germanium lens, as shown in Figure 4.

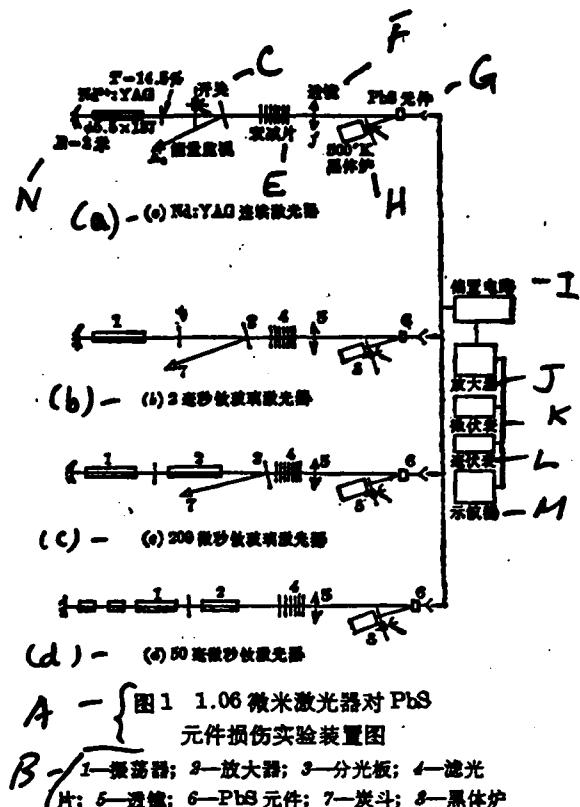
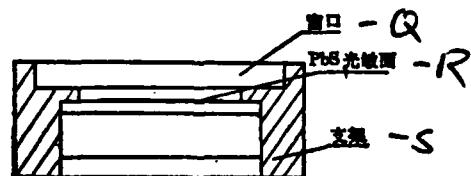
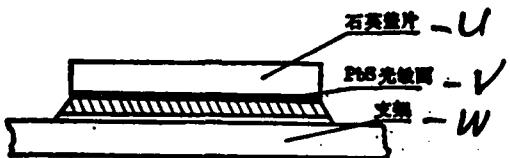


Figure 1. A. The set up for experiment of damage on PbS element by 1.06 micron laser device. B. 1 - oscillator, 2 - amplifier/magnifier, 3 - beam-splitter plate, 4 - light filter, 5 - lens, 6 - PbS detector, 7 - carbon tank, 8 - black body stove. C. valve, D. energy monitor, E. attenuator, F. lens, G. PbS detector, H. black body stove, I. bias circuit, J. magnifier/amplifier, K. microvolt meter, L. millivoltmeter, M. oscillosometer, N-R-2m, (a) - (a) Nd:YAG continuous laser device, (b) - (b) 2 millisecond Nd glass laser device, (c) - (c) 200 micro Nd glass laser device, (d) (d) 50 nanosecond Nd laser device.



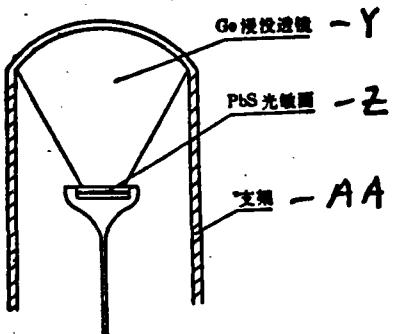
P - 图2 PbS元件示意图

P. Figure 2. PbS detector diagram, Q. window; R. PbS photo-sensitive surface, S. support rack.



丁一图3 有石英盖片的 PbS 元件示意图

T. Figure 3. Diagram of PbS detector with quartz slip cover;  
 V. PbS photo-sensitive surface, U. quartz slip cover; W. support  
 rack



丁-图4 Ge 淹没透镜 PbS 元件示意图

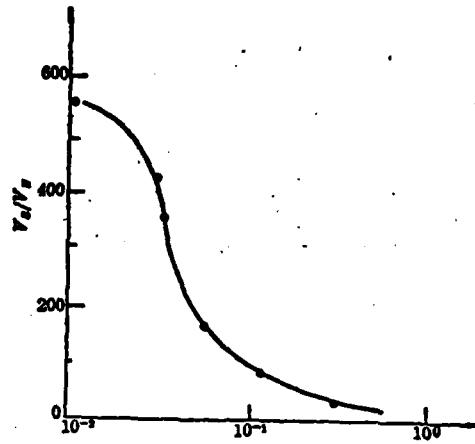
X. Figure 4. Diagram of PbS Ge-immersed lens, Y. Ge-doped lens.  
 Z. PbS photo-sensitive surface, AA - support rack

### III. Results of the experiments and their analyses

#### 1. The effect of laser irradiation on the performance of the PbS photo-sensitive detectors.

During the laser irradiation experiments, for short pulsedwidth laser ( $\tau < 2$  milliseconds), we measured the PbS signal-to-noise ratio  $V_s/V_n$  ( $V_s$  being signal and  $V_n$  being noise) before and after irradiation and the changes in resistance R. For experiments with laser of long pulsedwidth not only we can measure the change in performance of PbS before and after radiation, but also the change of  $V_s$  during the radiation process. The results of the measurements have been summarized as curves between signal-to-noise ratio and the radiation

energy density, in Figure 5, and curves between resistance and radiation energy density, as in Figure 6.

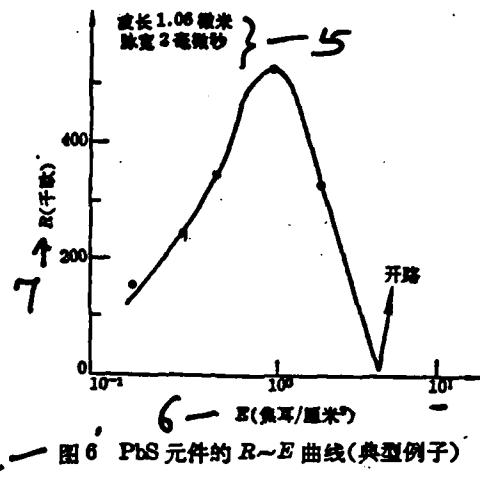


1 — 2 —  $E$ (焦耳/厘米<sup>2</sup>)  
图 5 PbS 元件的  $V_s/V_n \sim E$  曲线

波长 1.06 微米; 脉宽 50 纳秒;  $E_0 \sim 4.5 \times 10^{-2}$   
焦耳/厘米<sup>2</sup>;  $E_s \sim 4 \times 10^{-1}$  焦耳/厘米<sup>2</sup>

3 — (

Figure 5. 1. Figure 5 PbS detector  $V_s/V_n \sim E$  curve, 2.  $E$  (joule/cm<sup>2</sup>), 3. wavelength = 1.06 micron; pulselength = 50 nanoseconds;  $E_0 \sim 4.5 \times 10^{-2}$  joule/cm<sup>2</sup>;  $E_s \sim 4 \times 10^{-1}$  joule/cm<sup>2</sup>.



4—图6 PbS元件的R~E曲线(典型例子)

Figure 6. 4. Figure 6 PbS detector  $R \sim E$  curve (typical example, 5. Wavelength - 1.06 micron, pulse width= 2 nanoseconds, 6.  $E$  (joule/cm $^2$ ), 7.  $R$ (K  $\Omega$ ).

From analyses on the aforementioned curve with respect to signal-to-noise ratio ( $V_s/V_n$ ), the relationship between resistance ( $R$ ) and laser irradiation energy density ( $E$ ), and the corresponding surface damage situations, we can draw the following three conclusions:

(1) As  $E$  increases, changes in  $V_s/V_n$  and  $R$  vary from moderately slow to rapid changes. In the region of changes,  $V_s/V_n$  begins with a moderately slow change(the typical procession is a slow decrease, but for some other elements the curve will slowly rise and then fall), then pass through a stage before a quick fall. In this process, there are two clear characteristics. One of them is that at a certain time interval after the laser irradiation,  $V_s/V_n$  will increase to a higher value. The other characteristic is that the surface of the element will not show observable damage (even under a 40x microscope). We may conclude that decrease in  $V_s/V_n$  is a temporary deterioration. Its material composition, structure, and (electric) conductivity have not undergone any basic changes. Clearly, the above two characteristics are related. As for the corresponding  $R \sim E$

curve in this region, as  $E$  increases,  $R$  will first change slowly, then it will rapidly rise.

(2) When  $E$  continues to have small changes in quantity,  $V_s/V_n$  falls rapidly. After irradiation is ended, even after some time lapse the value of  $V_s/V_n$  cannot return to any higher value. At this time, the surface of the detector will have begun to show flight damage. In this region, when we decrease  $V_s/V_n$  to 50% of the initial value of the energy density, we have this value,  $E_o$ , the onset damage threshold value. Actually, under this condition, we say that the detector is damaged. As for the corresponding  $R \sim E$  curve in this region, when  $R$  reaches its maximum value, its corresponding  $E$  value is basically that of  $E_o$ . Since the detector surface has begun showing damage, and its performance characteristics cannot recover, this clearly shows that the detector's material composition has begun to change, and the damage has become permanent. We assess the situation by analytically computing the temperature (about 600°C) that can be achieved by the surface of the element at the time the onset damage threshold value is reached; the PbS material is not yet damaged because the temperature is still lower than the melting and vaporizing temperature (respectively at 1114°C and 1281°C). Note that in the sensitization of the PbS manufacturing process it is possible that some oxide and halide compounds of Pb are introduced, thereby lowering the melting temperature. For example  $PbO_2$ ,  $Pb_2O_3$ , and  $Pb_3O_4$  have the respective melting temperatures of 290°C, 370°C and 500°C. We can deduce from this, that with the damage onset threshold value of  $E_o$ , after the material has undergone laser irradiation, the apparent damage on the surface of PbS and the change in performance characteristics may be caused by the heat dissociation by one or many lead oxides.

(3) As the value of  $E$  continues to rise,  $V_s/V_n$  falls to the minimum value. We decrease  $V_s/V_n$  to 1% of

the initial value or to the value of  $E$  when the absolute value approaches 1, this is regarded as the critical damage threshold value  $E_s$ . Under this condition most of the PbS material will be lost through vaporization (this applies to the situation where the PbS optical segment is being irradiated by short pulse laser). As for the  $R \sim E$  curve, when  $E$  is increased more,  $R$  will quickly fall to a very small value (corresponding to  $E_s$ ). Now if  $E$  is further increased, the value of  $R$  will suddenly increase to infinity, leading to the open circuit, as shown in Figure 6. When  $R$  falls to a very small value (near the short circuit path), i.e., as the conductivity rapidly increases, this is possible in the PbS gas, some of the PbS will revert to metal. At this time we may observe, under a microscope, thin layers of glittering metal granules. As  $R$  reaches points of infinity, an open circuit path is formed, usually the following three phenomena appear: (1) the PbS on the detector will completely vaporize, leaving behind only quartz substrates and electrodes; (2) quartz substrate in pieces, or (3) severed electrode (welding) pads or severed electrodes.

Synthesizing the above analyses we may see that: under laser irradiation with continuously increasing energy density the PbS detector will degenerate from excellent material to a thoroughly damaged one, beginning with surface damage. Also, during this process, the characteristics of the PbS detector undergo some very complex changes in both quantity and quality, resulting from a multitude of processes.

## 2. The effect of laser pulsewidth on the damage threshold of PbS.

We will first describe the damage threshold values  $E_o$  and  $E_s$  (their respective power density damage thresholds being  $P_o$  and  $P_s$ ) determined by  $V_s/V_n \sim E$  and  $R \sim E$  curves. We use

different pulsed widths to draw the curves, i.e., to obtain energy damage threshold values (or power density damage threshold values) and the relational curves of the irradiating laser pulsed width ( $E_0$ ,  $E_s \sim \tau$ ,  $P_0 P_s \sim \tau$ ) as shown in Figure 7. In this region, as the pulsed width undergoes change of 8 orders of magnitude, the damage threshold values will change by 4 orders of magnitude. Looking at the entire curve, the damage threshold values  $E_0$ ,  $E_s$  increase as  $\tau$  does ( $P_0$  and  $P_s$  will decrease as  $\tau$  increases). In the region of short pulsed widths, the change in  $E_s$  is slower. In the continuous long pulsed width region,  $E_0$  and  $\tau$  have a linear relationship.

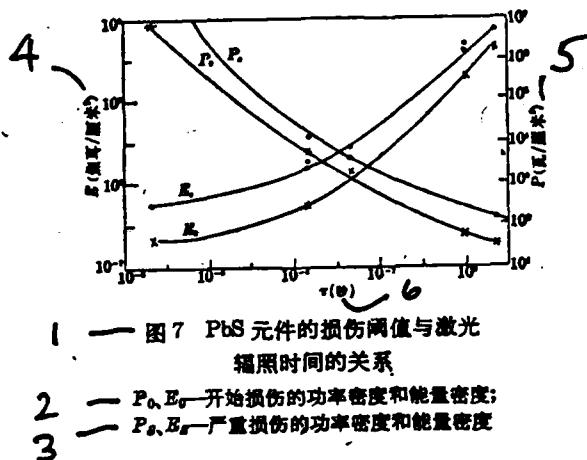


Figure 7. 1. Figure 7. The relationship between the damage threshold values of the PbS detector and the duration of laser irradiation, 2.  $P_0, E_0$  — the respective onset damage power density and energy density, 3.  $P_s, E_s$  — the respective severe decomposition power density and energy density, 4.  $E$  ( $\text{Joule}/\text{cm}^2$ ); 5.  $P$  ( $\text{W}/\text{cm}^2$ ), 6.  $\tau$  (seconds).

For the damage handling of PbS under laser irradiation, it is generally of the nature of dealing with effect of heat. Therefore, in the case of PbS optical segments we may use a thermal model of "uniform irradiating semi-infinite solids,"

and for the PbS detector with slip cover, we use model of "thin absorption layer sandwiched between two uniform irradiating plates." However, with lasers of different pulselength and different energy density, the changes in the characteristics of PbS detector with different structures and the mode of damage are rather complex. PbS has strong absorption ability for the 1.06 micron laser (the absorptivity is  $2 \times 10^4 \text{ cm}^{-1}$ ), and it has comparatively higher spectral sensitivity. Therefore, under the 1.06 micron laser irradiation PbS produces photocurrent, and its output signal is directly proportional to the irradiation intensity, i.e.,  $V_s \propto n$ . While observing the change in  $V_s$  of the PbS detector undergoing irradiation by lasers of long pulselength, we find that there exist a signal with its  $V_s$  value being scores of times the irradiation of a black body. Clearly, this is the irradiation signal of a 1.06 micron laser. It is caused by the direct transition of PbS absorbing photons of the 1.06 micron laser, thereby producing a large quantity of carrier rheotons [Translator's Note: I am at loss to translate this term: ~~载流子~~. Apparently this is purely the author's own, original, invention. It could very well been translated as carrier stray particle or carrier fluid particle, any of these will be appropriate in Chinese]. Furthermore, through the indirect transition (with corresponding  $10^{-3}$  ev) and due to the induced PbS temperature rise, a large quantity of acoustic particles. [Translator's Note: This again appears to be the author's own invented term]. Under the uniform irradiation of lasers with long pulselength, the heat in PbS has sufficient time to conduct its (heat) energy to quartz substrate (the thermal conductivity of PbS and molten quartz are respectively 0.024 and 0.014 w/cmK and the heating time constant of PbS thin film is approximately in the range of micro-to-milliseconds). This reaches the frame holding the detector and, it then irradiates to influence the existing damage caused by the convection energy. Therefore, the longer the pulselength (of laser used),

the higher will be the damage threshold. Under this situation, we may attribute the following as principal cause of damage; material decomposition through heat, thereby severing the welded component of the electrode, which causes melting of PbS material and partial vaporization. For lasers of short pulse-width, the damage caused by heat conduction, etc. is negligible. With lower energy density ( $E < E_0$ ), the damage is apparently done by melting, decomposition, and partial vaporization. We can observe, under microscope, molten material in the melting pit or in the vapor. When the irradiation energy density reaches the severe decomposition threshold ( $E > E_s$ ), PbS will primarily or completely vaporize. As for lasers of medium pulsedwidth, the extent of material damage will be somewhere between that of the long and short pulsedwidths.

### 3. The structure of PbS and the effect of experimental conditions on the damage threshold.

#### (1) The PbS detector with quartz window

Since the 1.06 micron laser has a permeability on molten quartz, then its damage threshold value does not differ basically from the windowless PbS detector. As for the PbS treated with high temperature as well as PbS manufactured with ammonia, the laser damage threshold values show significant differences.

#### (2) The PbS detector with quartz cover

The damage threshold value of PbS with this kind of structure is slightly lower than the windowless PbS. Even when its irradiation energy density reaches the severe decomposition threshold value  $E_s$  its surface will still not show observable, clear damage. Even at this time some vaporization may take place, but due to its being bonded tightly by quartz slip cover

and with condensation, the vaporized material will just solidify again. If we further raise the irradiation energy density, then, finally, the PbS material will be completely along the edges of the bonding material. A PbS detector with this kind of structure has a threshold value four to five times higher than the aforementioned material, for complete vaporization.

(3) PbS detector with immersed Ge lens and PbS with Ge window.

For continuous pulse (laser), the damage threshold value of PbS detector with doped lens is ten times higher than that of PbS detectors with quartz slip cover. The PbS detector with Ge window has a damage threshold value 40 times higher than that of PbS detectors with quartz slip cover. During the irradiation process (time = 30 seconds) we always discovered that the  $V_s$  signal rapidly increased by scores of times, this being similar to the  $V_s$  rise induced by the direct irradiation by a 1.06 micron laser. At this time, the PbS damage is mainly caused by the material on Ge lens and on Ge window having been irradiated by the laser; this induced higher temperatures resulting in heat conduction and heat radiation, and this caused rising temperatures in PbS adhesion and solder. When the irradiation energy density is lower, it causes  $V_s$  to fall, and if  $E$  is then raised, it will finally cause the decomposition of adhesive material and solder; the solder joint is loosened and an open circuit results. If we replace the Ge window with a piece of Ge, and set it apart from the photosensitive surface of PbS, then even when the irradiation energy density reaches 4 to 5 times higher than that which caused an open circuit in the PbS element of a Ge lens, evidence of severe damage will still fail to appear.

For lasers with short pulses, the onset damage threshold value of PbS detector with Ge lens and Ge window is 10 to 30

times higher than that with quartz slip covers. Furthermore, for PbS elements with Ge window, the irradiation energy density can even reach 160 joule/cm<sup>2</sup>; it will still not reach the stage of severe decomposition. Similar to the condition of long pulse with Ge elements and PbS being separated, at this time the fall of  $V_s$ , of the PbS signals, is usually caused by the lowered permeability of the blackbody radiation; this is induced by damage (crack lines, concavity, etc.) on the Ge surface material while under laser irradiation. Whether we have long or short pulse irradiation, the damage threshold value of PbS elements with Ge lens will always be lower than that with Ge window. This is probably due to the condensed coking of the Ge lens heat radiation and further direct heating on PbS.

(4) Effect of partial vaporization of the PbS material on the performance properties and damage threshold value.

We use a laser bundle of 2 mm diameter to irradiate a 6 x 6 mm<sup>2</sup> PbS photo-sensitive surface and vaporization will not cause severe decomposition of PbS detector. It is not related to either the effect on the properties of the element or the position of damage on the photo-sensitive surface, but it is related to the total damage area and the sequence of irradiation. After the first irradiation, 3.22 mm<sup>2</sup> of the photo-sensitive material is vaporized; at this time  $V_s$  falls by 50%. This shows that 10% of the photo-sensitive area suffered damage and vaporization; therefore the damage on the detector has begun (i.e.,  $E_o$  is reached).  $V_s$  continues to fall after the second and third irradiations. The stage of severe decomposition is reached after the fourth irradiation.

If the element is pressed while the laser is irradiating, the damage threshold value is about 30% when it is not.

4. The laser damage threshold value of a Ge segment and a Ge segment with a film of ZnS.

Different laser pulse widths have significantly differing damage threshold values on Ge and the Ge with  $Z_nS$  film on its surface. Under a continuous laser irradiation of 18 watts for 1 to 50 seconds, the surface of Ge shows almost no damage. Only when the irradiation energy density is greater than  $2 \times 10^4$  joule/cm<sup>2</sup> we find some shallow trace of damage in the  $Z_nS$  film. For short pulse lasers, at 2 milliseconds of irradiation the damage threshold value is 5 joule/mm<sup>2</sup> for ZnS film, and 20 joule/mm<sup>2</sup> for Ge (its surface shows molten groves and hairline cracks. For irradiation of 50 nanoseconds,  $Z_nS$  film has damage threshold values of 0.4 joule/mm<sup>2</sup>, and for Ge, 80 joule/mm<sup>2</sup> ).

#### IV. Conclusions

The study of the reaction between laser and semiconductor material has just begun. We have selected PbS for our study, i.e., to investigate the damage threshold value of PbS under irradiation of a 1.06 micron laser. This value varies according to the pulselwidth of the irradiating laser:  $E_o$  and  $E_s$  increase as  $\tau$  increases; when  $\tau$  is longer, they increase linearly. For PbS of different structure, the threshold value of the laser damage will be different. For the different PbS detectors that we have selected, their threshold values can differ by 30 to 40 times. The difference in the amount of partial vaporization of the PbS detector will influence the properties of the elements as well as the values of damage thresholds.

Consider Ge, which is used for windows in the PbS detector, and  $Z_nS$  film with respect to their thresholds of laser damage; we find through observation, clear evidence of dependence between damage threshold and pulselwidth.

Whether we have PbS of different structures or the material with Ge windows, their laser damage thresholds are much

lower than those of metals or dielectric material.

Furthermore, we have observed during the experiments that long before the initiation of damage by laser irradiation, the PbS element signal  $V_s$  displays the phenomenon of saturation and the ability of the 1.06 micron laser to penetrate the Ge segment. The experimental arrangement and procedures await further study. Under the influence of strong lasers, especially under the influence of lasers with super-short pulses, a semiconductor displays a non-linear optical phenomenon. In particular, for non-elastic light scattering experiments and theory, we need to study the interaction of photons with electrons, sound particles, laser particles, polarons, magnetized oscillations, and ions. We must clarify the energy band structure of semiconductors, electrical conductivity, and light generation. Based on this, we can expand the range of applications for lasers and semiconductors, and explore the important implications for developments in solid state physics.

#### REFERENCES

- [1] "1.06 微米毫秒激光辐照金属材料的实验研究",《中国科学院上海光机所研究报告集,第六集,钕玻璃高能激光器》,189~201 (1978).
- [2] "强激光热烧蚀的实验研究总结",《中国科学院上海光机所研究报告集,第六集,高能钕玻璃激光器》,202~210(1978).
- [3] M. K. Chun, K. Rose; *J. Appl. Phys.*, 1970, 41, 614.
- [4] J. F. Ready; "Effect of high-power laser radiation", 1971.
- [5] A. M. Prokhorov, V. A. Batanov et al.; *IEEE J. Quant. Electr.*, 1973, QE-9, 508.
- [6] F. W. Darry; *IEEE J. Quant. Electr.*, 1972, QE-8, 106.
- [7] S. A. Metz, L. R. Hettche et al.; *J. Appl. Phys.*, 1975, 44, 1634.
- [8] J. A. Fox; *Appl. Phys. Lett.*, 1975, 26, 683.
- [9] B. Stelzner, H. P. Duckel; *J. Appl. Phys.*, 1976, 47, 1940.
- [10] Y. Matsuoka et al.; *J. Phys. D: Appl. Phys.*, 1974, 7, 1259.
- [11] Y. Matsuoka et al.; *Appl. Phys. Lett.*, 1974, 25, 574.
- [12] F. Bartoli et al.; *J. Appl. Phys.*, 1973, 44, 3713.
- [13] M. R. Kruer et al.; *J. Appl. Phys.*, 1975, 46, 1072.
- [14] F. R. Bartoli et al.; *J. Appl. Phys.*, 1975, 46, 4591.
- [15] M. R. Kruer et al.; *Opt. and Quantum Electronics*, 1976, 8, 453.
- [16] M. Kruer et al.; *J. Appl. Phys.*, 1976, 47, 2867.